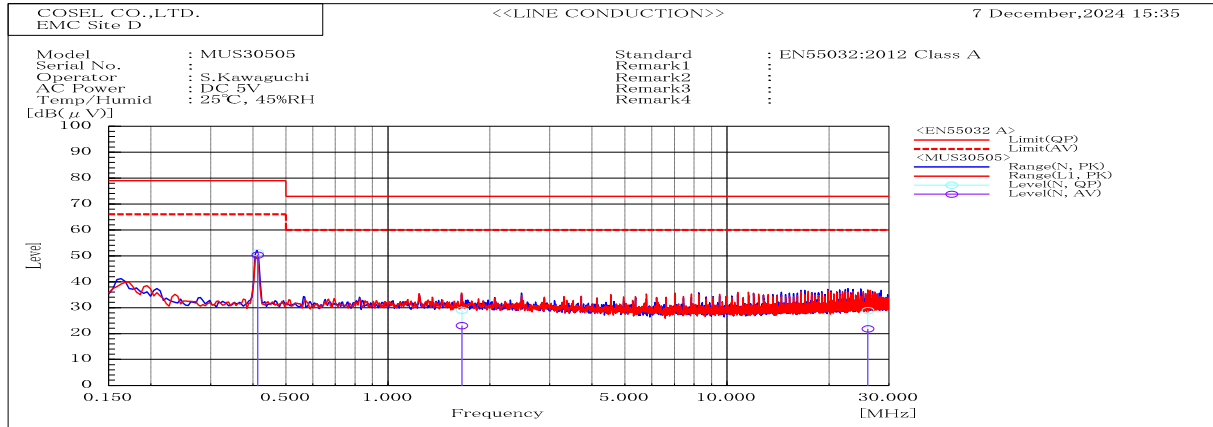
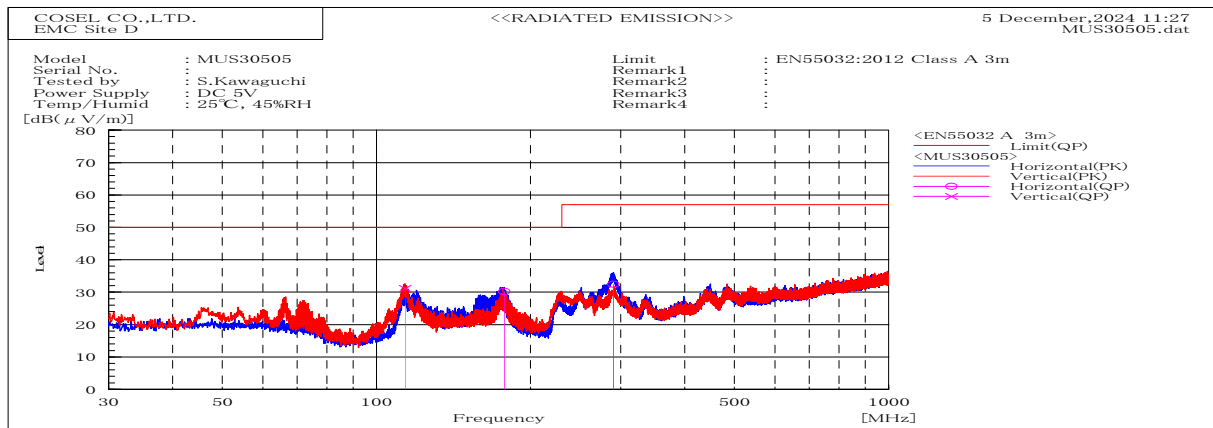


DATA SHEET

Model		MUS30505	Date	07-Dec-24
Test		EMI Line conduction & Radiated emission	Temp.	25 degreeC
			Humid.	45 %RH
			Tested by	S.Kawaguchi



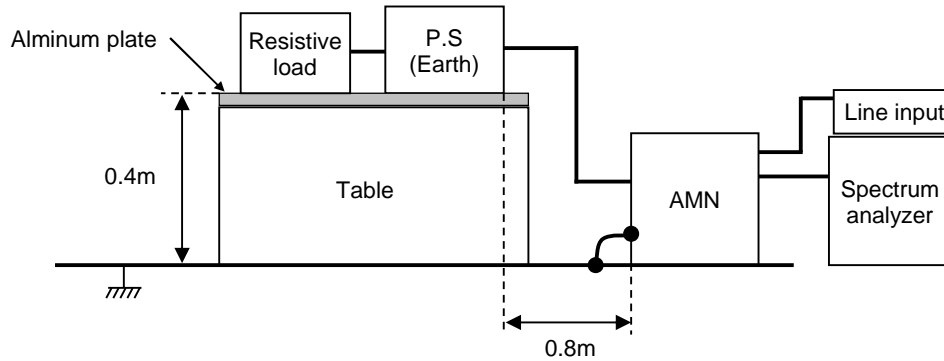
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.413	N	51.2	50.3	79	66	27.8	15.7	Pass	
1.652	N	29	23.1	73	60	44	36.9	Pass	
26.047	N	28.9	21.8	73	60	44.1	38.2	Pass	



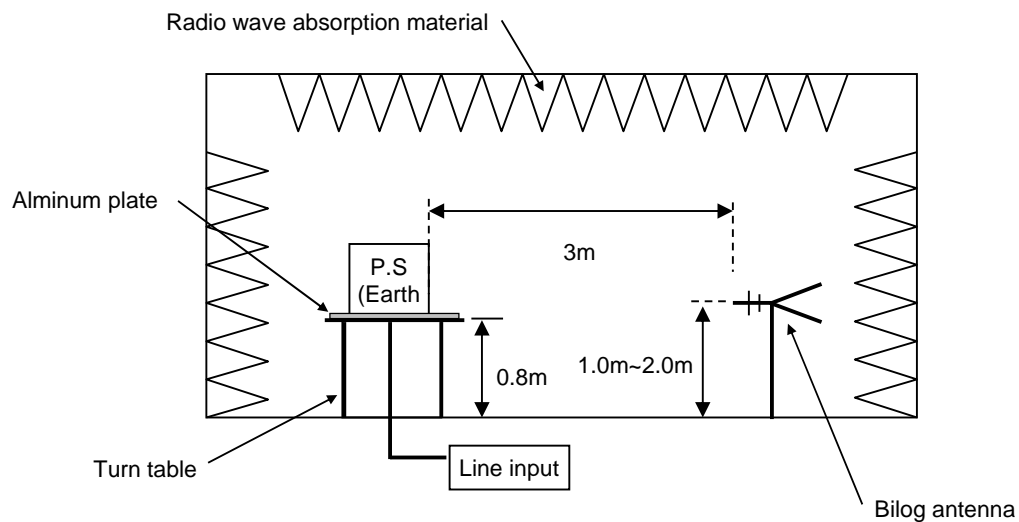
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV						
113.691	V	Stable	31.2	50	18.8	Pass	100.2	307.2		
177.792	H	Stable	30.2	50	19.8	Pass	199.7	248.6		
290.204	H	Stable	32.4	57	24.6	Pass	101.6	217.1		

DATA SHEET		Date	07-Dec-24
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

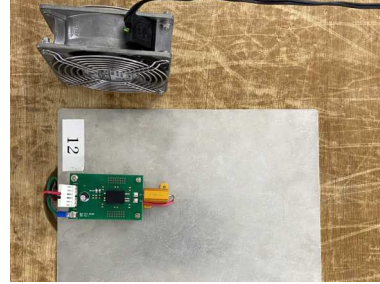
Test : EMI
Model Name: MUS3□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

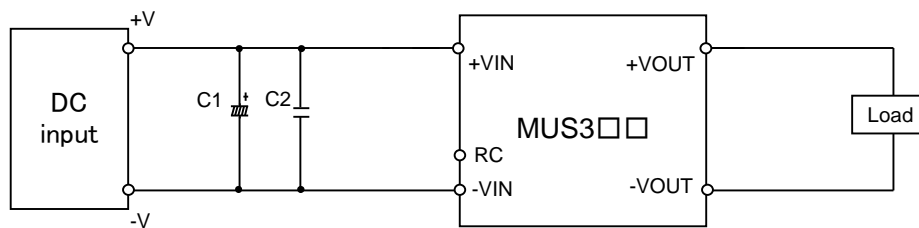


Fig.1 MUS305□, MUS312□, MUS324□ Testing circuitry

C1 :	MUS305□	16V 220 μ F	Electric capacitor (UPWseries NICHICON)
	MUS312□	50V 100 μ F	Electric capacitor (UPWseries NICHICON)
	MUS324□	-	
C2 :	MUS305□	16V 22 μ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUS312□	25V 22 μ F	Ceramic capacitor (C3216JB1E226MT TDK)
	MUS324□	50V 10 μ F	Ceramic capacitor (C3216X7R1H106KT TDK)

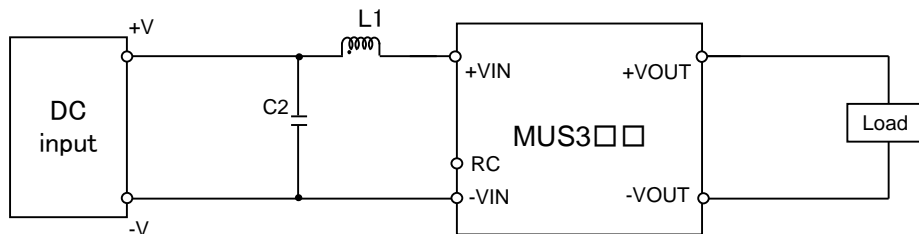


Fig.2 MUS348□ Testing circuitry

C2 :	MUS348□	100V 2.2 μ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUS348□	520mA 15 μ H	Inductor (LQH32PN150MN0L MURATA MANUFACTURING)